Se	arcn Notes
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Application/Control No.	Applicant(s)/Patent under Reexamination	_
10/006,999	FABER ET AL.	
Examiner	Art Unit	
Yubin Hung	2624	

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382	162,166 167,244 248,250 276	7/13/2006	YH
345	644	7/13/2006	YH
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SEARCH NO (INCLUDING SEARC)
	DATE	EXMR
EAST Text search (US_PGPUB, USPAT, EPO, JPO, DERWENT, IBM_TDB)	7/13/2006	ΥH
IEEE Xplore	11/29/2005	ΥH
ACM	1/9/2006	ΥH
SPIE	11/29/2005	ΥH